


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) | [Purchase History](#)

Welcome United States Patent and Trademark Office

[Search Results](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "((protocol attribute filter state flow)-in>metadata)"

Your search matched 0 of 2262483 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by **Relevance in Descending order**.

**Join IEEE Now
Save 50%**

[» Search Options](#)[View Session History](#)[New Search](#)

» Key

IEEE JNL	IEEE Journal or Magazine
IET JNL	IET Journal or Magazine
AIP JNL	AIP Journal
AVS JNL	AVS Journal
IEEE CNF	IEEE Conference Proceeding
IET CNF	IET Conference Proceeding
IEEE STD	IEEE Standard



Indicates open access content

Modify Search

((protocol attribute filter state flow)-in>metadata)

[Search](#)☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract[IEEE/IET/AIP/AVS](#)[Books](#)[Educational Courses](#)[A](#)

IEEE/IET journals, transactions, letters, magazines, conference proceedings, AIP standards.

[view selected items](#)[Select All](#) [Deselect All](#)**No results were found.**

Please edit your search criteria and try again. Refer to the Help pages if you need assistance.

[Help](#) [Contact Us](#)

Powered by
Inspection

© Copyright 2009